Preliminary Amendment

Applicant: Horst Groeninger Serial No.: Not yet assigned

(Priority Application No. 10 2004 007 696.0)

(International Application No. PCT/DE2005/000216)

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Docket No.: I431.172.101/FIN574PCT/US

Title: TEST APPARATUS FOR TESTING A SEMICONDUCTOR DEVICE, AND METHOD FOR

TESTING THE SEMICONDUCTOR DEVICE (as amended)

## IN THE SPECIFICATION

Please insert the following paragraph beginning at page 1, line 7, of the substitute specification with the following paragraph:

## Cross Reference to Related Application

This Utility Patent Application claims the benefit of the filing date of German Application No. DE 10 2004 007 696.0, filed February 16, 2004, and International Application No.PCT/DE2005/000216, filed February 9, 2005, both of which are herein incorporated by reference.